

Description

The HM6311 uses advanced trench technology to provide excellent $R_{\rm DS(ON)}$, low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

D G SOT-23-3L

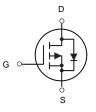
General Features

 $V_{DS} = -30V, I_{D} = -9.5A$

 $R_{DS(ON)} < 20m\Omega$ @ V_{GS} =-10V

Application

High power and current handing capability
Lead free product is acquired
Surface mount package
PWM applications
Load switch
Power management



P-Channel MOSFET

Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
HM6311	SOT-23-3L	30P10	3000PCS

Absolute Maximum Ratings (T_A=25 ℃ unless otherwise noted)

Symbol	Parameter		Max.	Units
V _{DSS}	Drain-Source Voltage		-30	V
V _{GSS}	Gate-Source Voltage		±20	V
I _D	Continuous Drain Current	T _A = 25℃	-9.5	Α
		T _A = 100°C	-5.5	Α
I _{DM}	Pulsed Drain Current note1		-46	Α
E _{AS}	Single Pulsed Avalanche Energy note2		35	mJ
P _D	Power Dissipation	T _A = 25℃	3.0	W
R _{0JA}	Thermal Resistance, Junction to Ambient		48	°C/W
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	$^{\circ}$



$\textbf{Electrical Characteristics} \ \, (T_J = 25\, ^{\circ} \! \text{C unless otherwise specified})$

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
Off Charac	Off Characteristic					
V _{(BR)DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D = -250μA	-30	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -30V, V _{GS} =0V,	-	-	-1	μA
I _{GSS}	Gate to Body Leakage Current	V _{DS} =0V, V _{GS} = ±20V	-	-	±100	nA
On Charac	On Characteristics					
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D = -250μA	-1.0	-1.6	-2.5	V
_	Static Drain-Source on-Resistance	V _{GS} = -10V, I _D = - 5A	-	14	20	
$R_{DS(on)}$	Note3	V _{GS} = -4.5V, I _D = -5A	-	19	27	mΩ
Dynamic (Characteristics					
C _{iss}	Input Capacitance	1-11	-	1330	-	рF
Coss	L Output Capacitance	V _{DS} = -15V, V _{GS} =0V, f=1.0MHz	-	183	-	pF
C _{rss}	Reverse Transfer Capacitance	1-1.0WII 12	-	156	-	pF
Qg	Total Gate Charge	V _{DS} = -15V, I _D = -5A, V _{GS} = -10V	-	22	-	nC
Q _{gs}	Gate-Source Charge		-	1.0	-	nC
Q_{gd}	Gate-Drain("Miller") Charge	V GS= -10 V	-	1.8	-	nC
Switching	Characteristics					
t _{d(on)}	Turn-on Delay Time	V _{DD} = -15V, I _D = -10A,	-	9	-	ns
t _r	Turn-on Rise Time		-	13	-	ns
t _{d(off)}	Turn-off Delay Time	V_{GS} =-10V, R_{GEN} =2.5 Ω	-	48	-	ns
t f	Turn-off Fall Time		-	20	-	ns
Drain-Sou	rce Diode Characteristics and Maximui	m Ratings				
Is	Maximum Continuous Drain to Source Diode Forward Current		-	-	-9.5	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	-46	Α
V_{SD}	Drain to Source Diode Forward Voltage	V _{GS} =0V, I _S = -15A	-	-0.8	-1.2	V
trr	Reverse Recovery Time	TJ=25℃,	-	64	-	ns
Qrr	, 3	V _{DD} = -24V,I _F =-2.8A, dI/dt=-100A/µs	-	25	1	nC

Notes:1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

- 2. EAS condition: T_J =25 $^{\circ}$ C, V_{GS} =10V, R_G =25 Ω , L=0.5mH, I_{AS} =-12.7A
- 3. Pulse Test: Pulse Width≤300µs, Duty Cycle≤0.5%



Typical Performance Characteristics

Figure1: Output Characteristics

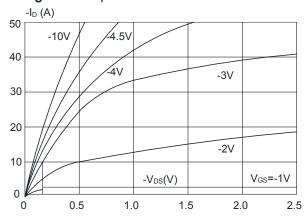


Figure 3:On-resistance vs. Drain Current

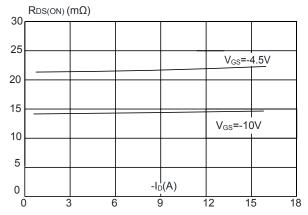


Figure 5: Gate Charge Characteristics

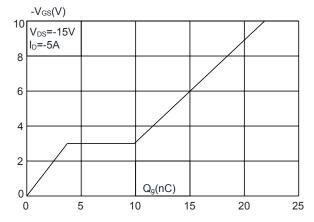


Figure 2: Typical Transfer Characteristics

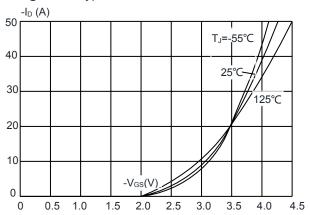


Figure 4: Body Diode Characteristics

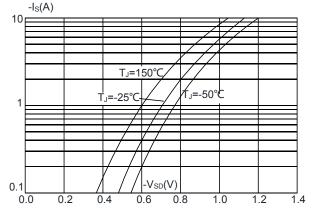


Figure 6: Capacitance Characteristics

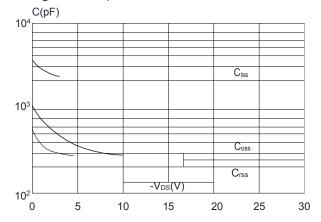




Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

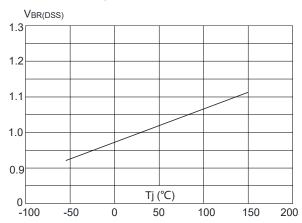


Figure 9: Maximum Safe Operating Area

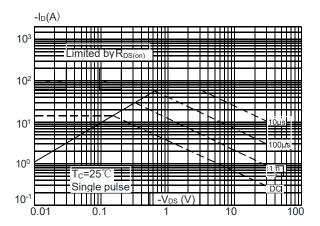


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case

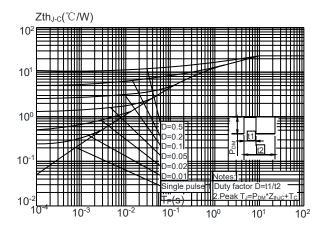


Figure 8: Normalized on Resistance vs. Junction Temperature

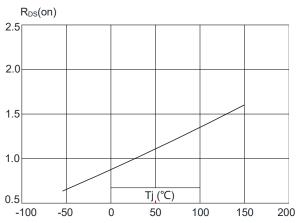
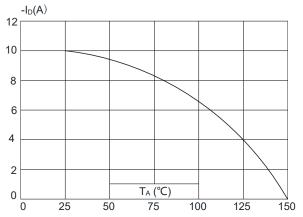


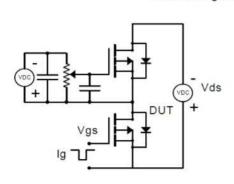
Figure 10: Maximum Continuous Drain Current vs. Ambient Temperature

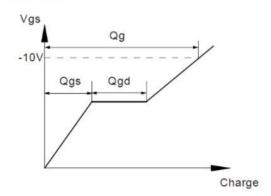




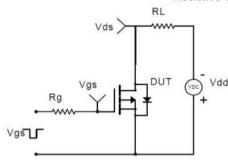
Test Circuit

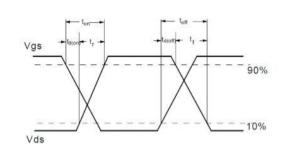
Gate Charge Test Circuit & Waveform



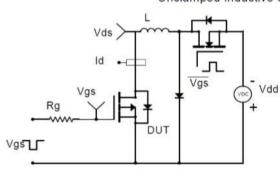


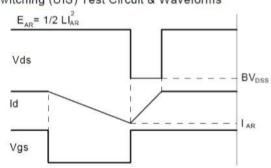
Resistive Switching Test Circuit & Waveforms



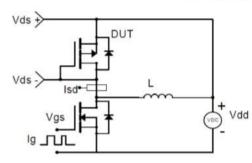


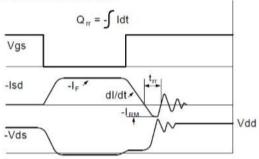
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





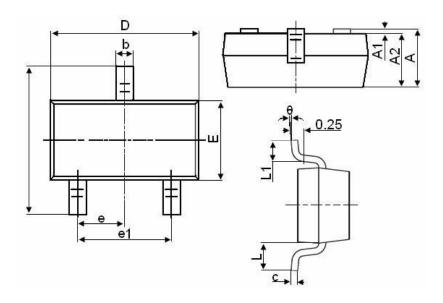
Diode Recovery Test Circuit & Waveforms







SOT-23-3L Package Information



Symbol	Dimensions in Millimeters		
	MIN.	MAX.	
А	1.050	1.250	
A1	0.000	0.100	
A2	1.050	1.150	
b	0.300	0.500	
С	0.100	0.200	
D	2.800	3.000	
E	1.500	1.700	
E1	2.650	2.950	
е		0.950TYP	
e1	1.800	2.000	
L		0.550REF	
L1	0.300	0.600	
θ	0°	8°	



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